

Materials and Methods

TXRF development and application

TXRF's early development

Since Yoneda [1-3] used total reflection technique to XRF for the first time in 1971, they have been able to identify uranium in saltwater, iron in blood, and rare earth elements in hot spring water.

Theoretical underpinnings and experimental settings were later examined. Wobrauschek conducted a doctoral thesis on the issue in Vienna, Austria [14], and he and Aiginger reported detection limits of nanograms [1-5] [1-6]. Knoth and Schwenke discovered element evidence at the ppb level at Geesthacht, Germany, which is close to Hamburg [1-7] [1-8]. Following 1980, a wide range of uses encouraged a burgeoning interest, leading to a rise in the number of instruments in use to about 200 globally. The first total reflection X-ray fluorescence spectrometer for commercial use was successfully created in 1981 by the West German Rich Seifer Corporation. The TXRF instrument has since been rapidly developed and enhanced in both development and application. Several TXRF lectures have been held abroad since 1984 [1-9]. The Institute of High Energy Physics [1], the Institute of Modern Physics [2], and the Chinese Academy of Atomic Energy have led China in the creation of TXRF analysis equipment as well as the study and promotion of analysis techniques since the 1990s.

Table 1: TXRF early development goes through numerous significant phases.

Time	Representatives	Main work
1971	Yoneda Y, Horiuchi T	First proposed to apply total reflection technology to XRF
1978	Knoth, J. and Schwenke, H	Found element traces on the ppb-level
1981	Rich Seifer West Germany	Successfully developed the first commercial total reflection X-ray fluorescence spectrometer
1983	Becker	Studied the relationship between fluorescence intensity and angle below the critical angle
1986	Iida, A., Yoshinaga, A	Apply synchrotron radiation to TXRF
1991	Wobrauschek, Aiginger, Schwenke, and Knoth	Won the distinguished Bunsen-Kirchhoff Prize for the development of TXRF
1997	Klockenkamper	Publication of the first monograph on TXRF

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Electrons in atoms characteristic X-rays produced ionisation or excitation correspond to particular atoms based on their energy. Both qualitative and quantitative analysis of the elements is possible using Moseley's law. Total reflection reduces the background count significantly because the primary rays are released in the incident direction and can rarely be detected by the detector. The incident and wide reected waves interfere creating

Conclusion

With the initial use of total reflection technology for XRF in 1971, 50 years have passed. In this time, TXRF has advanced quickly. The background brought on by scattering has been eliminated using XRF, allowing for the analysis of ultra-trace components. It addresses the issue of multiple measurements.

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We can successfully complete the paper with the aid of our peers and professors.

Competing Interest

According to the authors, they have no competing interests that would prevent this study from being published.

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